

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|--|--|------------------|---------|------------------|
| S1 | 38 | first solution with (hf or "nh.sub.4f") and second solution with (alkali or HF or acid) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 20:31 |
| S2 | 21 | first solution with (hf or "nh.sub.4f") and second solution with (alkali or HF or acid) and semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 19:45 |
| S3 | 32 | first near solution with (hf or "nh. sub.4f") and second near solution with (alkali or HF or acid) and semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 19:45 |
| S4 | 1 | defect same etch\$3 and evaluat\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 20:40 |
| S5 | 3124 | defect same etch\$3 and evaluat\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 20:40 |
| S6 | 551 | defect same etch\$3 and evaluat\$4 and hf | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 20:40 |
| S7 | 13 | defect same etch\$3 and evaluat\$4 and hf and "Nh.sub.4f" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:44 |
| S8 | 4 | defect same etch\$3 same evaluat\$4 and hf and "Nh.sub.4f" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/21 20:46 |

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| S9 | 103 | defect same etch\$3 same evaluat\$4 and hf | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:24 |
| S10 | 26 | crystal defect same etch\$3 same evaluat\$4 and hf | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:42 |
| S11 | 252 | crystal defect and (secco or sertl or wright) with etch\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:43 |
| S12 | 42 | crystal defect same (secco or sertl or wright) with etch\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:45 |
| S13 | 4 | crystal defect same (secco or sertl or wright) with etch\$4 and second near solution | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:44 |
| S14 | 4 | crystal defect and (secco or sertl or wright) with etch\$4 and second near solution | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:53 |
| S15 | 4 | crystal defect and (secco or sertl or wright) same etch\$4 and second near solution | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:53 |
| S16 | 1 | crystal defect and evalut\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:54 |

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| S17 | 0 | crystal defect and evalutuat\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:54 |
| S18 | 2209 | crystal defect and evaluat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 07:54 |
| S19 | 16 | crystal defect same evaluat\$3 same reference | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:43 |
| S20 | 0 | crystal defect same evaluat\$3 same reference wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 08:07 |
| S21 | 1 | crystal defect same evaluat\$3 same reference area | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 08:08 |
| S22 | 1 | crystal defect and evaluat\$3 same reference area | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 08:08 |
| S23 | 4 | crystal defect and evaluat\$3 and reference area | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 08:12 |
| S24 | 448 | (438/5).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:15 |

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| S25 | 418 | (438/7).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:16 |
| S26 | 253 | (438/8).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:16 |
| S27 | 0 | ("crystaldefect and hf with concentration").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2006/07/24 09:03 |
| S28 | 154 | crystal defect and hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 18:38 |
| S29 | 39 | crystal defect and evaluat\$3 and hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:03 |
| S30 | 1 | crystal defect and evaluat\$3 and hf with concentration and defect free | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:04 |
| S31 | 1 | crystal defect and evaluat\$3 and hf with concentration and defect-free | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:04 |
| S32 | 39 | crystal defect and evaluat\$3 and hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:28 |

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| S33 | 1 | crystal defect and evaluat\$3 and defect free reference | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:06 |
| S34 | 10 | crystal defect and evaluat\$3 and defect free with reference | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:20 |
| S35 | 0 | crystal defect and evaluat\$3 and defect free with reference image | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:08 |
| S36 | 1 | crystal defect and evaluat\$3 and defect free and reference image | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:08 |
| S37 | 1 | crystal defect and defect free and reference image | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:08 |
| S38 | 185 | defect free and reference image | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:08 |
| S39 | 8 | defect free and reference image and hf | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:08 |
| S40 | 2 | crystal defect and evaluat\$3 and defect free with reference and no defect | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:20 |

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| S41 | 11 | crystal defect and evaluat\$3 and ((defect free) or (no defect)) with reference | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:21 |
| S42 | 47 | crystal defect and (evaluat\$3 or detection) and hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:28 |
| S43 | 1 | crystal defect and (evaluat\$3 or detection) same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:30 |
| S44 | 1 | crystal defect and (evaluat\$3 or detection) same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 09:30 |
| S45 | 36 | defect and (evaluat\$3 or detection) same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:43 |
| S46 | 0 | defect and (evaluat\$3 or detection) same hydrofluoric with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:01 |
| S47 | 220 | defect and (evaluat\$3 or detection) and hydrofluoric with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:01 |
| S48 | 12 | defect and (evaluat\$3 or detection) same hydrofluoric with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:08 |

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| S49 | 58 | crystal defect and (evaluat\$3 or detection) same hf | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:09 |
| S50 | 1 | crystal defect and (evaluat\$3 or detection) same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:10 |
| S51 | 10 | crystal defect same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:35 |
| S52 | 152 | ultrasonic wave same etch\$3 same clean\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:37 |
| S53 | 23 | ultrasonic wave same etch\$3 same clean\$3 and hf | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:37 |
| S54 | 45 | ultrasonic wave same etch\$3 same known | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:37 |
| S55 | 13 | ultrasonic wave same etch\$3 same known same clean\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/07/24 10:37 |
| S56 | 2 | ("20050208322").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/22 10:18 |

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| S57 | 167 | crystal defect and hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 18:38 |
| S58 | 2 | "20050208322" | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 18:43 |
| S59 | 10 | etch\$3 same crystal defect and device pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 19:49 |
| S60 | 257 | etch\$3 same crystal defect and device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 19:49 |
| S61 | 44 | selective\$2 with etch\$3 same crystal defect and device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 20:07 |
| S62 | 6 | selective\$2 with etch\$3 same crystal defect same device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:44 |
| S63 | 0 | ("257e21.53").PN. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/08 20:27 |

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| S64 | 955 | (257/e21.53).CCLS. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/11 03:43 |
| S65 | 61 | S64 and etch\$3 and crystal with defect | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 20:30 |
| S66 | 49 | S64 and etch\$3 and crystal with defect and pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 20:30 |
| S67 | 35 | S64 and etch\$3 and crystal with defect and device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:44 |
| S68 | 3 | S64 and crystal with defect and etch\$3 same device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/08 20:36 |
| S69 | 2 | "20050208322" | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:12 |
| S70 | 521 | (438/5).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/11 03:42 |

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| S71 | 20 | crystal defect same evaluat\$3 same reference | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:43 |
| S72 | 451 | (438/7).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/11 03:43 |
| S73 | 269 | (438/8).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/11 03:43 |
| S74 | 45 | defect and (evaluat\$3 or detection) same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:43 |
| S75 | 955 | (257/e21.53).CCLS. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/11 03:43 |
| S76 | 955 | (257/e21.53).CCLS. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:16 |
| S77 | 35 | S76 and etch\$3 and crystal with defect and device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:44 |

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| S78 | 6 | selective\$2 with etch\$3 same crystal defect same device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:16 |
| S79 | 15 | defect same etch\$3 and evaluat\$4 and hf and "Nh.sub.4f" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/06/11 03:44 |
| S80 | 4 | crystal defect same (secco or serti or wright) with etch\$4 and second near solution | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:17 |
| S81 | 541 | (438/5).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:15 |
| S82 | 462 | (438/7).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:16 |
| S83 | 273 | (438/8).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:16 |
| S84 | 981 | (257/e21.53).CCLS. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/22 22:16 |
| S85 | 6 | selective\$2 with etch\$3 same crystal defect same device with pattern | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:16 |

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| S86 | 5 | crystal defect same (secco or serti or wright) with etch\$4 and second near solution | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:17 |
| S87 | 46 | defect and (evaluat\$3 or detection) same hf with concentration | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:17 |
| S88 | 46 | S87 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:21 |
| S89 | 10 | SUGAMOTO-JUNJI.in. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:23 |
| S90 | 80 | TSUCHIYA-NORIHIKO .in. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:22 |
| S91 | 171 | USHIKU-YUKIHIRO .in. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:23 |
| S92 | 83 | TANZAWA-KATSUJIRO .in. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/09/22 22:23 |